

Workshop and Demo

Imaging Ellipsometry

CHALMERS 2019

May 23rd, Gothenburg

Dear everyone,

We are happy to invite you to learn more about Imaging Ellipsometry and our Ellipsometric Platform nanofilm_EP4.

Imaging Ellipsometry allows to visualize and to characterize graphene and 2D-materials, ultra thin films, monolayers, OPV, MEMS SAMs etc. or more generally speaking, the measurement of optical constants and thicknesses with a lateral resolution down to 1 μm at surfaces or solid/liquid, air/water and oil/water interface.

We will start with a seminar, including three talks, followed by showing the instrument at work and the opportunity for hands on instrument. (If you are interested in a time slot to have a brief view on your samples, please send an E-mail for registration)

We are looking forward to see you in Gothenburg!



Program

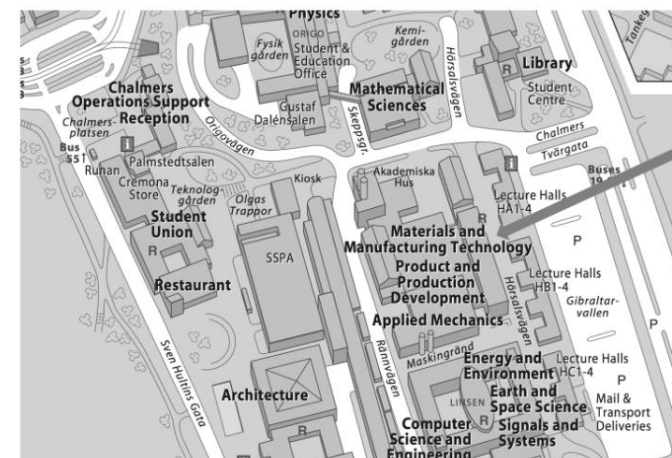
- 10:00 – 12:00 *Seminar*
 VINCENZO PALERMO: Graphene and 2D-materials at CHALMERS
 PETER H. THIESEN: Applications of Imaging Ellipsometry – An Overview
 SHUN OKANO: Characterization of Graphene and 2D-Materials by Imaging Ellipsometry
- 12:00 – 13:00 *Lunch break*
- 13:00 – 14:00 EP4@work – demo of the Spectroscopic Imaging Ellipsometer nanofilm_EP4
- 14:00 – open end Time slots for hands on instrument (30 min for each group, registration required)

Arrival

Chalmers University of Technology
 Department of Industrial and Materials Science
 Ground floor, Building M-huset,
 Hörsalsvägen 7A/7B

Meeting room: **DELTA**

GOOGLE MAPS LINK
<https://goo.gl/maps/kJV9gCyBwxH2>



Contact



Dr. Peter H. Thiesen

pt@accurion.com
 +49(0)551/99960-20
 +49(0)1520/9996020 (mobile)



Accurion GmbH
 Stresemannstraße 30
 37079 Goettingen,
 Germany



Shun Okano

sok@accurion.com
 +49(0)551/99960-29

Accurion GmbH
 Stresemannstraße 30
 37079 Goettingen,
 Germany